Emye



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: HO et al.

Application No.: 09/782,446

Filed: February 12, 2001

Title: USE OF AMMONIA FOR ETCHING

ORGANIC LOW-K DIELECTRICS

Attorney Docket No.: LAM1P152/P0692

Examiner: VINH, Lan

Group: 1765

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the U.S. Postal Service with sufficient postage as first-class mail on March 9, 2004 in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

Alexandria, VA 22515-145

Signed:

Sue Funchess

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR §§1.56 AND 1.97

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

The issue fee in the above-identified patent application was paid on January 21, 2004. The references listed in the attached PTO Form 1449 became known to Applicants after payment of the issue fee. Under their duty of disclosure, Applicants hereby submit copies of the cited references. Although it is discretionary at this point, Applicants respectfully request that the Examiner consider these references and make these references of official record in this application.

This Information Disclosure Statement is not to be construed as a representation that a search has been made, that additional information material to the examination of this application does not exist, or that these references indeed constitute prior art.

If it is determined that any fees are due, the Commissioner is hereby authorized to charge such fees to Deposit Account 50-0388 (Order No. LAM1P152).

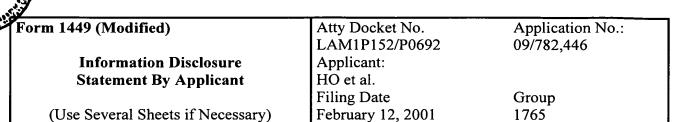
Respectfully submitted,

BEYER WEAVER & THOMAS, LLP

Michael Lee

Registration No. 31,846

P.O. Box 778 Berkeley, CA 94704-0778 (831) 655-2300



U.S.	Patent	Documents
------	--------	------------------

Examiner						Sub-	Filing
Initial	No.	Patent No.	Date	Patentee	Class	class	Date
	A	2001/0024769 A1	09/27/01	Donoghue et al.	430	329	02/08/01
	В	2002/0081855 A1	06/27/02	Jiang et al.	438	694	09/28/01
	С						
	D						
	E						
- "	F						
	G						
	Н				1		
	I						

Foreign Patent or Published Foreign Patent Application

Examiner		Document	Publication			Sub-	Translation	
Initial	No.	No.	Date	Patent Office	Class	class	Yes	No
• • •	J							
	K							
	L							
	M	·		-				
	N							

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	0	
1	P	
	Q	
Examiner	<u> </u>	Date Considered

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.